### TOSHIBA MOS DIGITAL INTEGRATED CIRCUIT SILICON GATE CMOS

# 131,072-WORD BY 8-BIT CMOS STATIC RAM

### DESCRIPTION

The TC558128BJ/BFT is a 1,048,576-bit high-speed static random access memory (SRAM) organized as 131,072 words by 8 bits. Fabricated using CMOS technology and advanced circuit techniques to provide high speed, it operates from a single 5 V power supply. There are two control inputs. Chip enable ( $\overline{ ext{CE}}$ ) can be used to place the device in a low-power mode, and output enable (OE) provides fast memory access. This device is well suited to cache memory applications where high-speed access and high-speed storage are required. All inputs and outputs are directly TTL compatible. The TC558128BJ/BFT is available in a plastic 32-pin SOJ (400 mil width) and TSOP packages for high density surface assembly.

### **FEATURES**

- Fast access time (the following are maximum values) Single power supply voltage of 5 V  $\pm$  10%. TC558128BJ/BFT-12: 12 ns TC558128BJ/BFT-15:15 ns

  - Fully static operation

• Package:

- All inputs and outputs are TTL compatible
- Output buffer control using  $\overline{OE}$
- Low-power dissipation (the following are maximum values)

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Cycle Time	12	15	20	25	30	ns
Operation (max)	190	170	140	130	120	mA

Standby: 1 mA (both devices)

#### **PIN ASSIGNMENT**

TC558128BJ	TC558128BFT
A3 [ 1 32 ] A4 A2 [ 2 31 ] A5 A1 [ 3 30 ] A6 A0 [ 4 29 ] A7 CE [ 5 $(28) = 0CE$ I/O1 [ 6 $(27) = 26 = 1/07$ VDD [ 8 $(27) = 26 = 1/07$ VDD [ 10 $(23) = 1/06$ I/O4 [ 11 $(22) = 1/05$ WE [ 12 $(21) = 21$ ] A8 A16 [ 13 20 ] A9 A15 [ 14 19 ] A10 A14 [ 15 18 ] A11 A13 [ 16 17 ] A12 (SOJ)	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$
(LOS)	(TSOP)

# SOJ32-P-400-1.27A (BJ)

TSOP II 32-P-400-0.80C (BFT) (Weight: 0.34 g typ)

(Weight: 1.22 g typ)

#### **PIN NAMES**

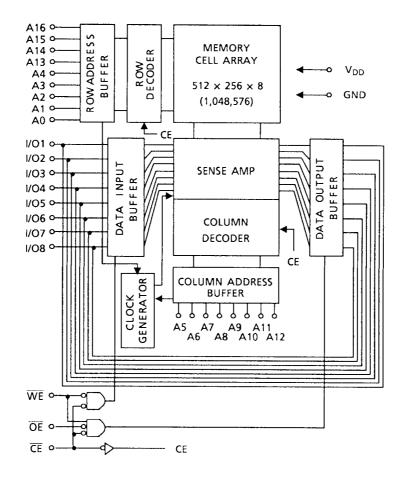
A0 to A16	Address Inputs
1/01 to 1/08	Data Inputs/Outputs
CE	Chip Enable
WE	Write Enable Input
ŌĒ	Output Enable
V <sub>DD</sub>	Power (+ 5 V)
GND	Ground

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# **BLOCK DIAGRAM**



### MAXIMUM RATINGS

SYMBOL	RATING	VALUE	UNIT
V <sub>DD</sub>	Power Supply Voltage	- 0.5 to 7.0	v
VIN	Input Terminal Voltage	- 2.0 * to 7.0	V
V <sub>1/O</sub>	Input/Output Terminal Voltage	- 0.5 * to V <sub>DD</sub> + 0.5	V
P <sub>D</sub>	Power Dissipation	1.1	W
T <sub>solder</sub>	Soldering Temperature (10 s)	260	°C
T <sub>strg</sub>	Storage Temperature	- 65 to 150	°C
T <sub>opr</sub>	Operating Temperature	- 10 to 85	°C

\*: I/O pins : -2.0 V with a pulse width of 20% · Cycle Time min(4 ns max) Other pins : -2.5 V with a pulse width of 20% · Cycle Time min(4 ns max)

# <u>DC RECOMMENDED OPERATING CONDITIONS</u> (Ta = $0^{\circ}$ to $70^{\circ}$ C)

SYMBOL	PARAMETER	MIN	ТҮР	МАХ	UNIT
V <sub>DD</sub>	Power Supply Voltage	4.5	5.0	5.5	v
V <sub>IH</sub>	Input High Voltage	2.2	-	V <sub>DD</sub> + 0.5	v
V <sub>IL</sub>	Input Low Voltage	- 0.5 *		0.8	v

\*: I/O pins : -1.5 V with a pulse width of 20% · Cycle Time min(4 ns max) Other pins : -2.0 V with a pulse width of 20% · Cycle Time min(4 ns max)

# <u>DC CHARACTERISTICS</u> (Ta = $0^{\circ}$ to $70^{\circ}$ C, V<sub>DD</sub> = 5 V ± 10%)

SYMBOL	PARAMETER	TEST CONDITION		MIN	TYP	МАХ	UNIT
Ι <sub>ΙL</sub>	Input Leakage Current	$V_{IN} = 0 V$ to $V_{DD}$		-		± 10	μA
ILO	Output Leakage Current	$\overline{CE} = V_{IH} \text{ or } \overline{WE} = V_{IL} \text{ or } \overline{OE} = V_{IH}$ $V_{OUT} = 0 \text{ V to } V_{DD}$		-	-	± 10	μA
I <sub>ОН</sub>	Output High Current	V <sub>OH</sub> = 2.4 V		- 4	-	-	mA
I <sub>OL</sub>	Output Low Current	$V_{OL} = 0.4 V$		8	-	-	mA
			tcycle = 12 ns	-	-	190	
			tcycle = 15 ns	-	-	170	
IDDO	Operating Current	$\overline{CE} = V_{IL}$ , lout = 0 mA	tcycle = 20 ns	-	_	140	mA
000		Other Inputs = $V_{IH}$ or $V_{IL}$	tcycle = 25 ns	-	_	130	
			tcycle = 30 ns	-	-	120	
I <sub>DDS1</sub>		$\overline{CE} = V_{IH}$ , Other Inputs = $V_{IH}$ or $V_{IL}$		-	_	30	
I <sub>DDS2</sub>	Standby Current	$\overline{CE} = V_{DD} - 0.2 V$ Other Inputs = V <sub>DD</sub> - 0.2 V or 0.2 V		_	_	1	mA

# CAPACITANCE (Ta = 25°C, f = 1.0 MHz)

SYMBOL	PARAMETER	TEST CONDITION	МАХ	UNIT
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> = GND	6	pF
C <sub>I/O</sub>	Input/Output Capacitance	$V_{I/O} = GND$	8	pF

Note: This parameter is periodically sampled and is not 100% tested.

# **OPERATING MODE**

MODE	CE	ŌĒ	WE	I/O1 to I/O8	POWER
Read	L	L	Н	Output	IDDO
Write	L	×	L	Input	IDDO
Outputs Disable	L.	н	н	High Impedance	IDDO
Standby	н	×	×	High Impedance	I <sub>DDS</sub>

X: Don't care

# <u>AC CHARACTERISTICS</u> (Ta = $0^{\circ}$ to $70^{\circ}$ C <sup>(Note 1)</sup>, V<sub>DD</sub> = 5 V ± 10%)

# READ CYCLE

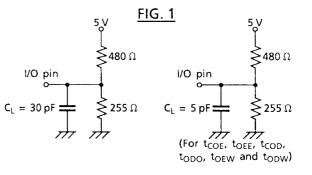
	PARAMETER	TC558128	TC558128BJ/BFT-12		BJ/BFT-15	
SYMBOL	PARAIVIETER	MIN MAX	MIN	MAX	UNIT	
t <sub>RC</sub>	Read Cycle Time	12	-	15	-	
t <sub>ACC</sub>	Address Access Time	-	12	_	15	
t <sub>co</sub>	Chip Enable Access Time	-	12	-	15	
t <sub>OE</sub>	Output Enable Access Time	-	6	-	8	
t <sub>OH</sub>	Output Data Hold Time from Address Change	5	_	5	-	ns
t <sub>COE</sub>	Output Enable Time from Chip Enable	5	_	5	_	
t <sub>OEE</sub>	Output Enable Time from Output Enable	1	_	1	_	
t <sub>COD</sub>	Output Disable Time from Chip Enable	-	6	_	8	
t <sub>opo</sub>	Output Disable Time from Output Enable	-	6	_	8	

#### WRITE CYCLE

CVMDOI	DADAMETED	TC55812	BBJ/BFT-12	TC558128	BJ/BFT-15	
SYMBOL	PARAMETER	MIN	MAX	MIN	MAX	UNIT
t <sub>wc</sub>	Write Cycle Time	12	-	15	_	
t <sub>WP</sub>	Write Pulse Width	8	-	9	-	
t <sub>CW</sub>	Chip Enable to End of Write	10	-	12	-	
t <sub>AW</sub>	Address Valid to End of Write	10	-	12	_	
t <sub>AS</sub>	Address Setup Time	0	-	0		
t <sub>WR</sub>	Write Recovery Time	0	-	0	_	ns
t <sub>DS</sub>	Data Setup Time	6	-	8	-	
t <sub>DH</sub>	Data Hold Time	0	-	0	-	
t <sub>OEW</sub>	Output Enable Time from Write Enable	1	-	1	-	
t <sub>opw</sub>	Output Disable Time from Write Enable	-	6	-	8	

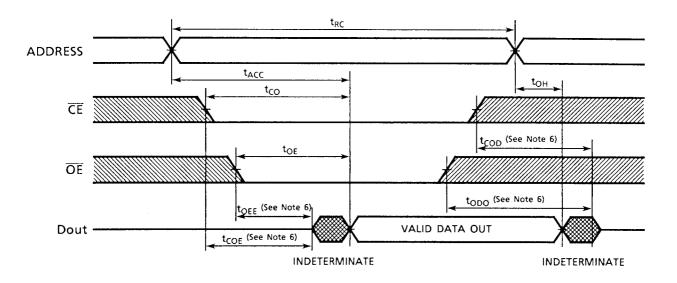
# AC TEST CONDITIONS

Input Pulse Level	3.0 V, 0.0 V
Input Pulse Rise and Fall Time	3 ns
Input timing Measurement Reference Level	1.5 V
Output Timing Measurement Reference Level	1.5 V
Output Load	Fig. 1

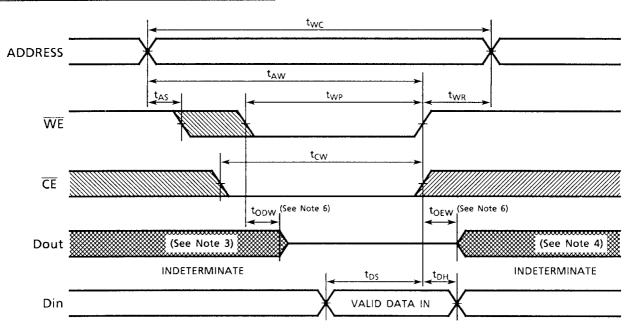


# **TIMING DIAGRAMS**

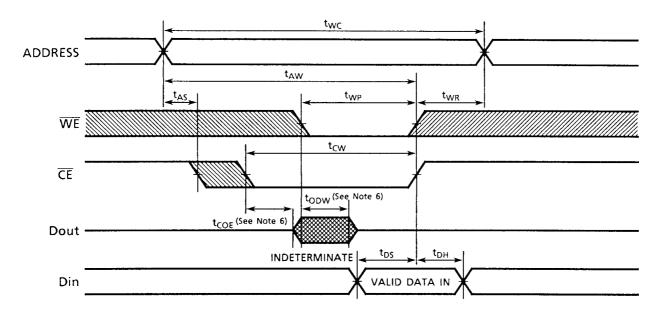
READ CYCLE (See Note 2)



### WRITE CYCLE 1 (WE CONTROLLED) (See Note 5)



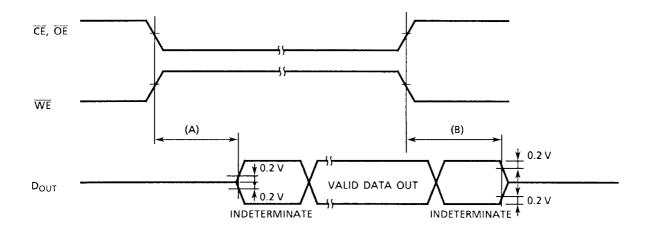
### WRITE CYCLE 2 (CE CONTROLLED) (See Note 5)



- Note: (1) Operating temperature (Ta) is guaranteed for transverse air flow exceeding 400 linear feet per minute.
  - (2)  $\overline{\text{WE}}$  remains HIGH for the Read Cycle.
  - (3) If  $\overline{CE}$  goes LOW coincident with or after  $\overline{WE}$  goes LOW, the outputs will remain at high impedance.
  - (4) If  $\overline{CE}$  goes HIGH coincident with or before  $\overline{WE}$  goes HIGH, the outputs will remain at high impedance.
  - (5) If  $\overline{OE}$  is HIGH during the write cycle, the outputs will remain at high impedance.

(6) The parameters specified below are measured using the load shown in Fig. 1.

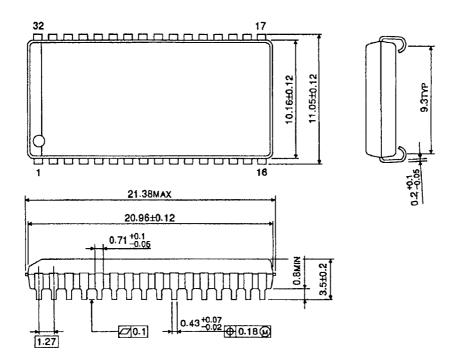
- (A) t<sub>COE</sub>, t<sub>OEE</sub>, t<sub>OEW</sub> Output ..... Enable Time
- (B) t<sub>COD</sub>, t<sub>ODO</sub>, t<sub>ODW</sub> Output ..... Disable Time



# PACKAGE DIMENSIONS

Plastic SOJ (SOJ32-P-400-1.27A)

Units in mm

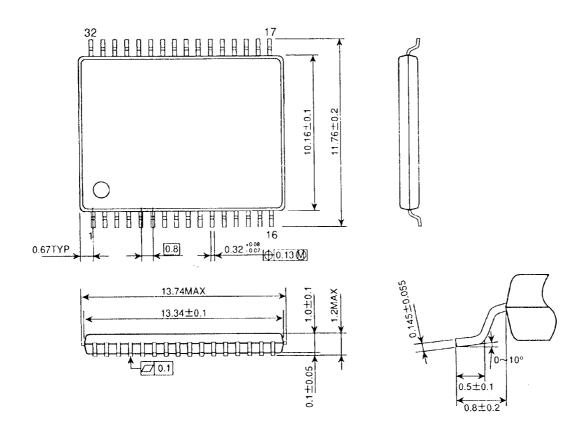


Weight: 1.22 g (typ)

### PACKAGE DIMENSIONS

Plastic TSOP (TSOP II 32-P-400-0.80C)

Units in mm



Weight: 0.34 g (typ)